

<b>Notice of References Cited</b>	Application/Control No. 09/834,736		Applicant(s)/Patent Under Reexamination STEIN, GIDEON P.	
	Examiner CUONG H. NGUYEN		Art Unit 3661	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,501,848	12-2002	Carroll et al.	382/128
*	B	US-6,460,127	10-2002	Akerib, Avidan	712/10
*	C	US-6,424,430	07-2002	Bilodeau et al.	358/1.2
*	D	US-6,313,840	11-2001	Bilodeau et al.	345/423
*	E	US-6,128,046	10-2000	Totsuka et al.	348/590
*	F	US-6,097,839	08-2000	Liu, Lingnan	382/181
*	G	US-5,717,781	02-1998	Ebel et al.	382/141
*	H	US-4,910,786	03-1990	Eichel, Paul H.	382/199
*	I	US-6,424,430	07-2002	Bilodeau et al.	358/1.2
*	J	US-6,097,839	08-2000	Liu, Lingnan	382/181
	K	US-			
*	L	US-5,233,670	08-1993	Dufour et al.	382/197
*	M	US-5,189,710	02-1993	Holt, Kenneth C.	382/273

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	WO 9205518 A	04-1992	World Intellect	HOLT, K C	
*	O	EP 473476 A	03-1992	European Patent	DUFOUR et al.	
*	P	CA 2047811 A	02-1992	Canada	DUFOUR et al.	
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Mazumder, J. et al., Method and apparatus for noncontact surface contour measurement, (US Pat. 5,446,549 filed 01/14/1993), DialogClassic Web(TM) file 6, acc. no. 1937442.
*	V	Tian, Aliling et al., Three-dimensional profile measurement of objects with spatially isolated surfaces by modified temporal phase unwrapping, Journal of Xi'an Jiaotong university, vol. 36 no. 11, 11/2004, pp.1196-1198.
*	W	Li, Quing et al., Lane boundary detection using an adaptive randomized Hough transform, Conference Proceedings v5 2004, Fifth World Congress on Intelligent Control and Automation, date: 6/15/2004.
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.